

Search Notes

Application/Control No.

10/073,495

Examiner

Tse Chen

Applicant(s)/Patent under
Reexamination

STEVENS, ET AL.

Art Unit

2116

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
text search only see "rpt prtotl"		TSE